

Low charge-mobility and defect-tolerance in *Soft* polar crystals is *Fundamental!* *The case of halide perovskites*

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The combination of properties halide perovskites (HaPs) possess (e.g., high absorption coefficient, low defect density, long carrier lifetimes, etc.) should (and does) allow high-performing optoelectronic devices. Their relatively low carrier mobility, however, is one fundamental property that does not fit the expected prognosis. When comparing mobility values of HaP ($1\text{-}100\text{ cm}^2\text{V}^{-1}\text{s}^{-1}$) with high-quality heteropolar semiconductors, such as GaAs or CdTe ($10^3\text{-}10^5\text{ cm}^2\text{V}^{-1}\text{s}^{-1}$), a significant difference is revealed. **Here we show that mobility temperature dependence of HaPs, as well as other low-defect density heteropolar semiconductors, is found to exhibit scattering by ‘polar optical phonons’ (POP), or dipoles formed during thermal fluctuations.** We explain why the mobility in *soft* heteropolar materials, like HaPs, will never be as high as for other, more rigid, heteropolar semiconductors, but also show that their softness is responsible for the potential to be more defect-tolerant than more rigid systems.

1 Charge mobility temperature dependence

Charge mobility: $\mu_q = \frac{q \cdot \tau_s}{m^*}$; Scattering frequency: $\frac{1}{\tau_{total}} = \frac{1}{\tau_{s1}} + \frac{1}{\tau_{s2}} + \dots$

$$\frac{1}{\mu_{total}} = \frac{1}{\mu_{II}} + \frac{1}{\mu_{NI}} + \frac{1}{\mu_{ADP}} + \frac{1}{\mu_{ODP}} + \frac{1}{\mu_{PZ}} + \frac{1}{\mu_{POP}}$$

Ionized impurities	$\mu_{II} \propto \frac{T^{+3/2}}{N_I}$	$N_I \equiv$ Ionized impurity density
Neutral impurities	$\mu_{NI} \propto \frac{T^0}{N_N}$	$N_N \equiv$ Neutral impurity density (relevant mostly at low temperatures)
Acoustic phonons	$\mu_{ADP} \propto \frac{T^{-3/2}}{d'^2}$	$d' \equiv$ deformation potential
Polar acoustic phonons	$\mu_{PZ} \propto \frac{T^{-1/2}}{e_{pz}^2}$	$e_{pz} \equiv$ piezoelectricity constant
Polar optical phonons*	$\mu_{POP} \propto \epsilon^* \cdot \frac{T^{1/2}}{\theta} \cdot \left(\exp\left(\frac{\theta}{T}\right) - 1 \right)$	$\theta \equiv$ Debye temperature = $\frac{\hbar \cdot \omega_{LO}}{k_B}$
		$\omega_{LO} \equiv$ longitudinal optical phonon ;
		$\epsilon^* \equiv$ effective dielectric constant

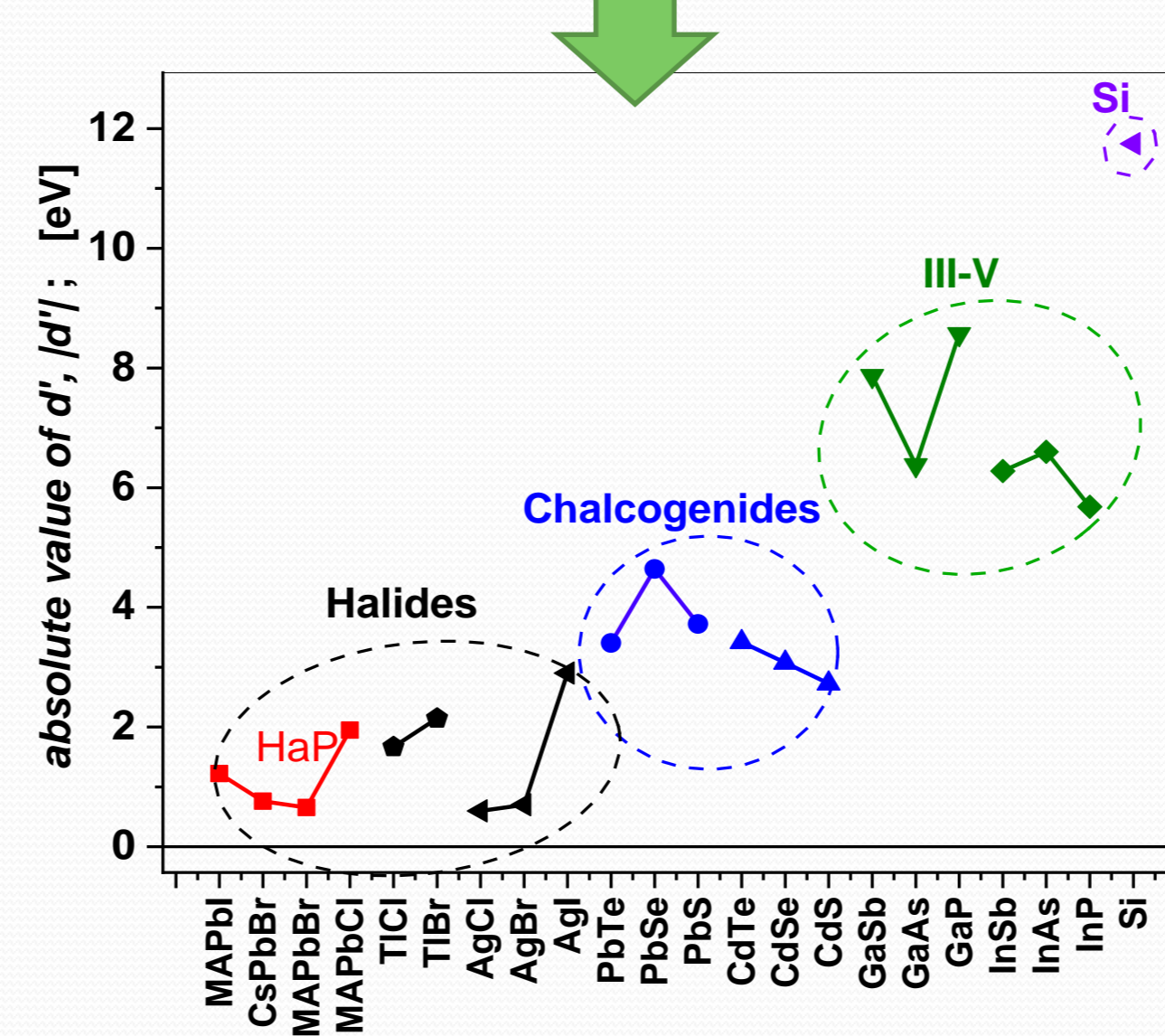
Theory and explicit equations can be found in:

- Li, S. S. *Semiconductor Physical Electronics*. (Springer-Verlag, 2006), Chapter 8
- Lundstrom, M. *Fundamentals of Carrier Transport*, 2nd edn. Meas. Sci. Technol. 13, 230 (2002).

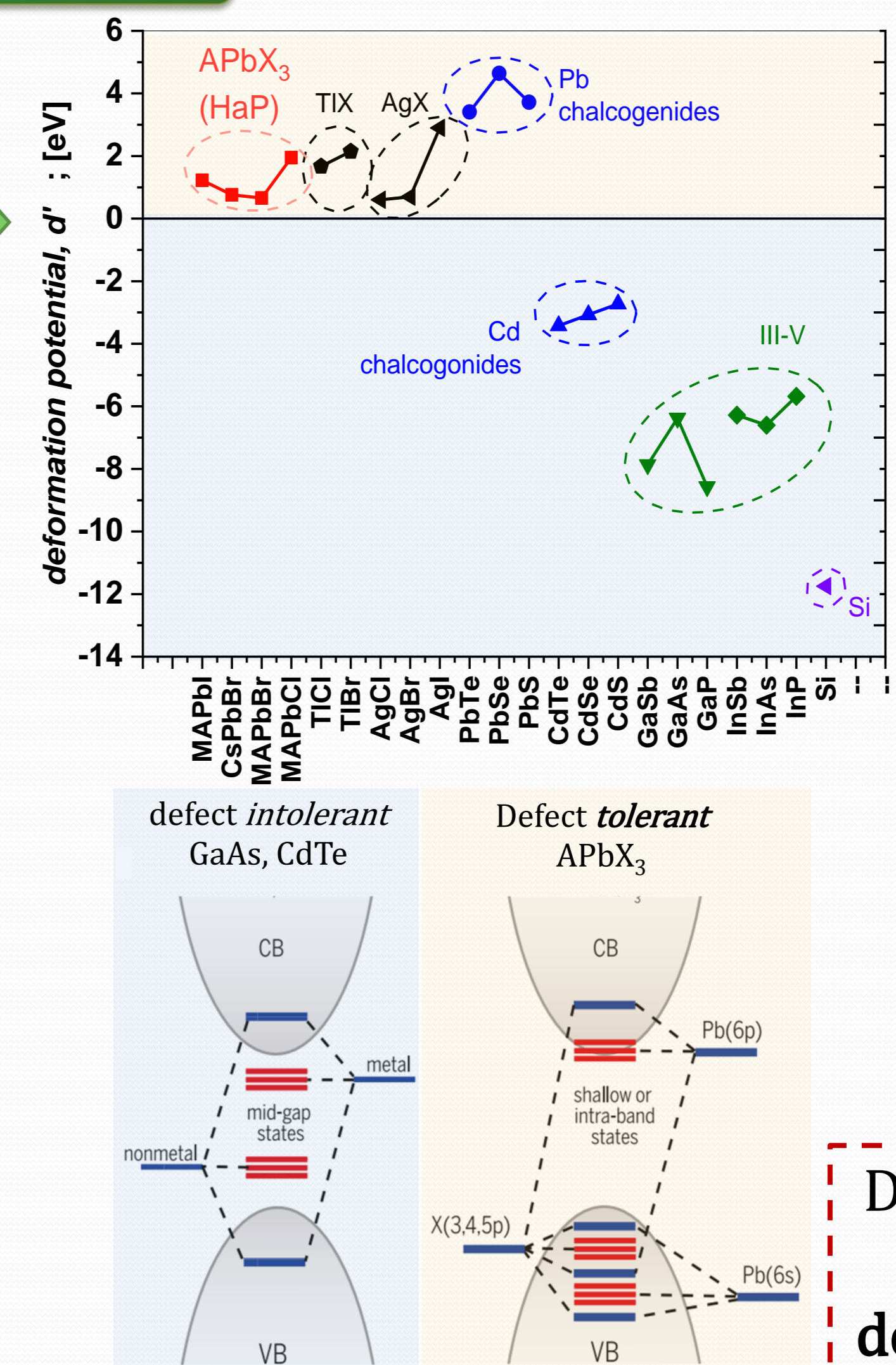
2 Deformation potential, d'

$$d' \equiv -B \cdot \frac{\Delta E_g}{\Delta P}$$

B – bulk modulus
 ΔE_g – change in bandgap
 ΔP – change in pressure



Halide-based materials have relatively low absolute deformation potential



Adopted from: Kovalenko et al., *Science* 358, 745–750 (2017)

Defect states in the bands = defect tolerance

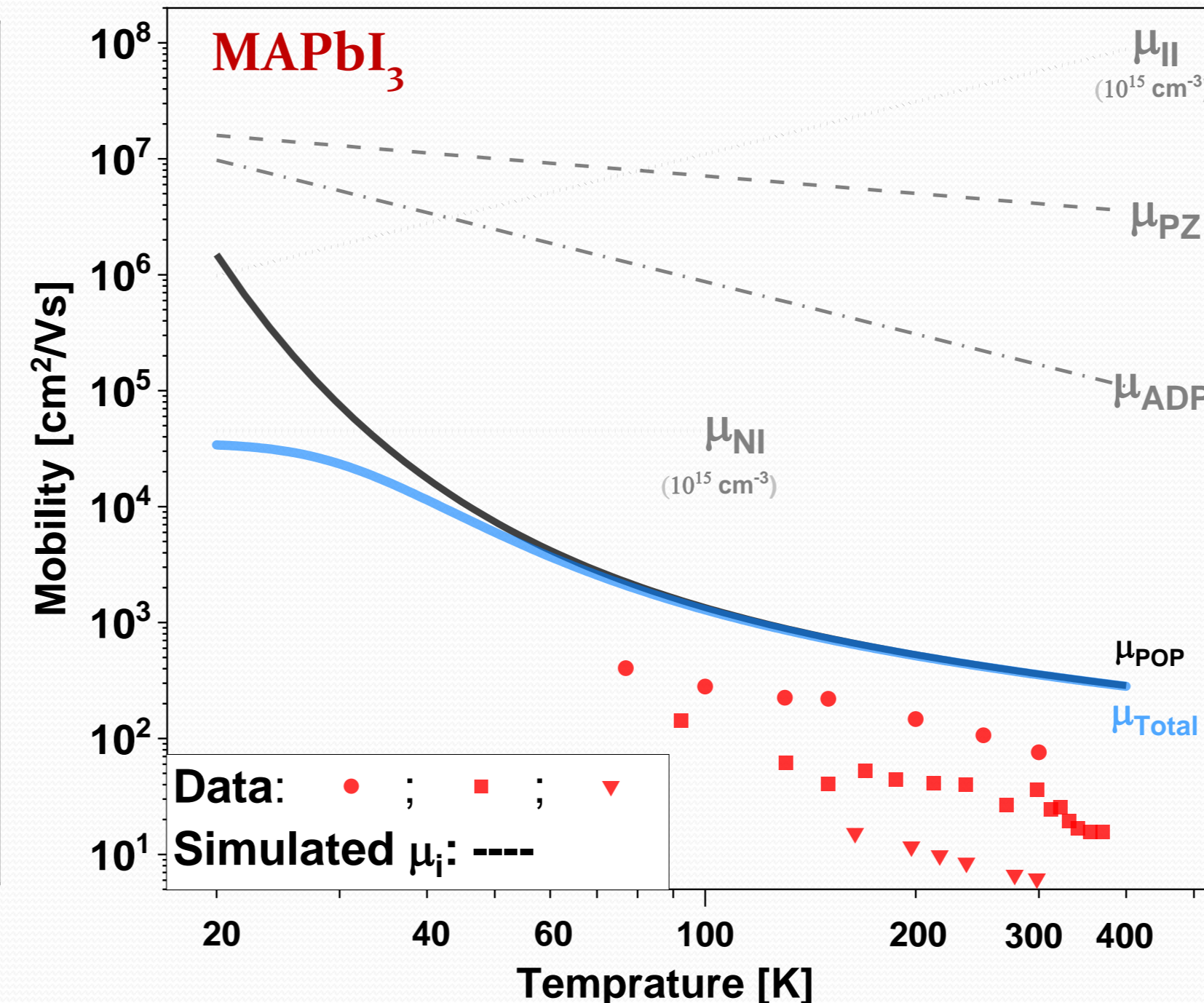
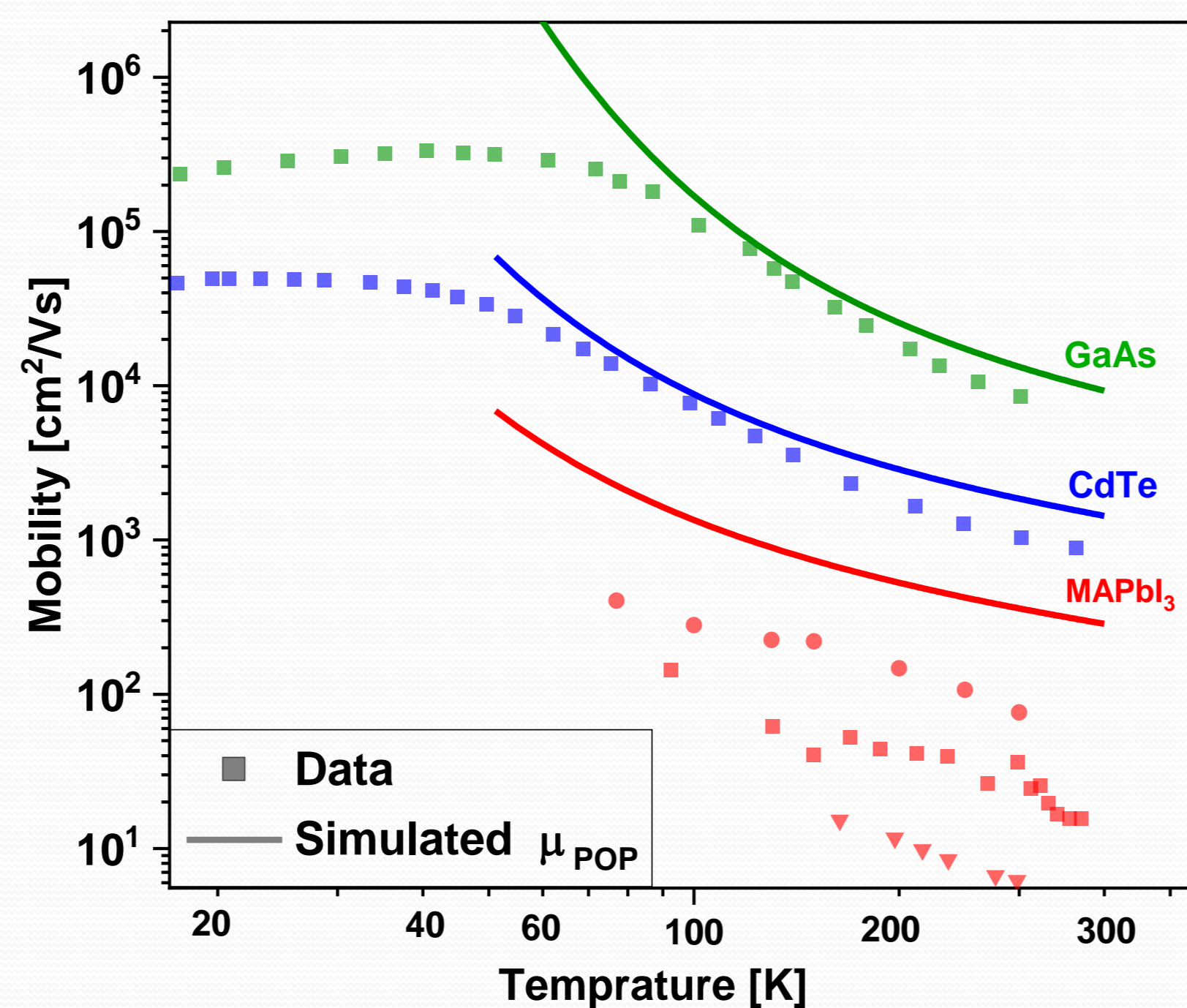
Results

3 Temperature dependence

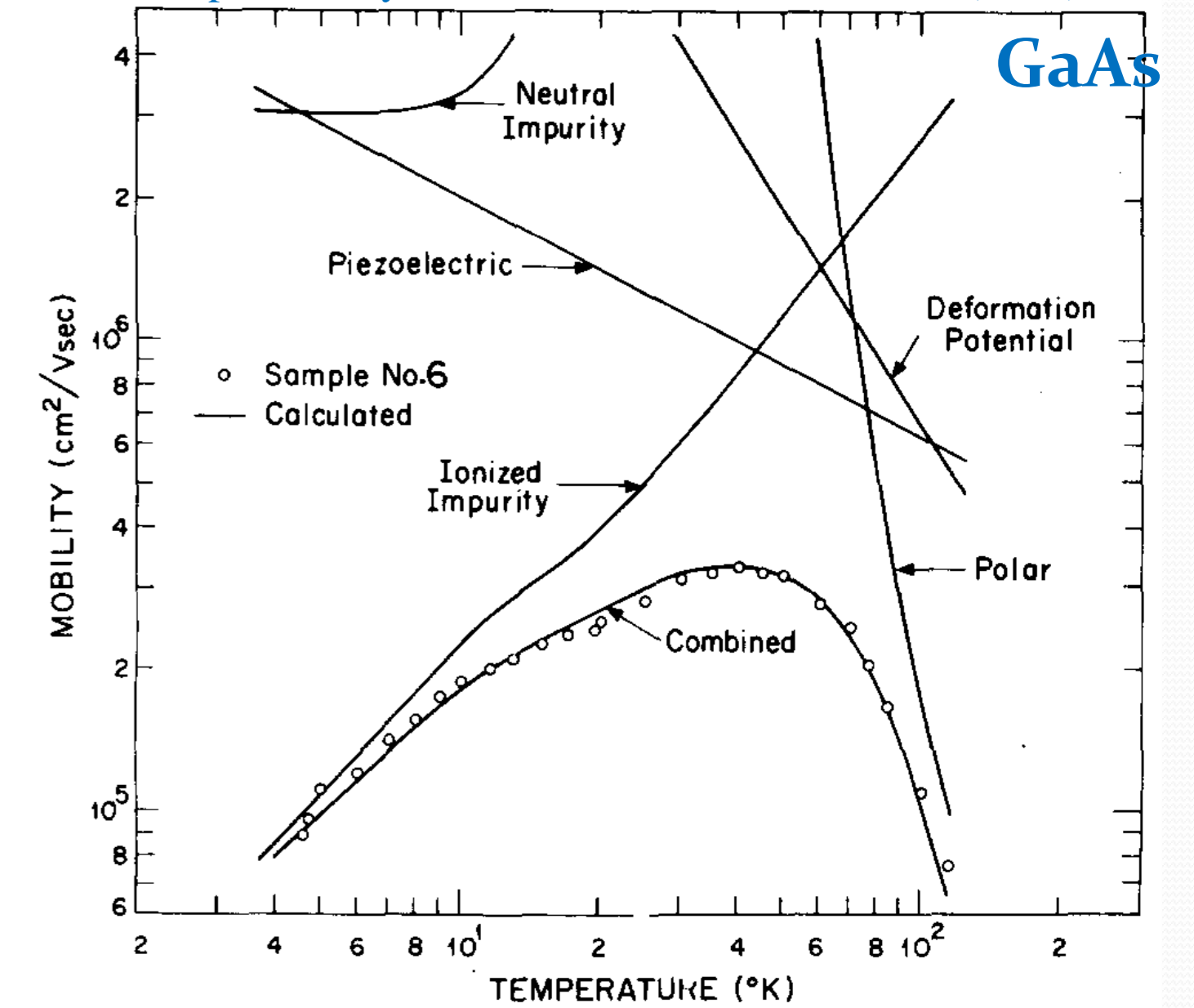
Using experimentally-based relevant parameters (from literature) such as: effective mass (m^*), lowest longitudinal optical phonon frequency (ω_{LO}), the dielectric constant at optical (ϵ_∞) and static/low (ϵ_s) frequencies and defect density (Ionized, N_I , at high temp.; neutralized, N_N , at low temp.) of 10^{15} cm^{-3} :

POP dominates scattering in heteropolar materials

The softer the materials (i.e., lower $|d'|$), the higher the probability that the scattering will be due to POP, rather than by deformation potential or impurities.

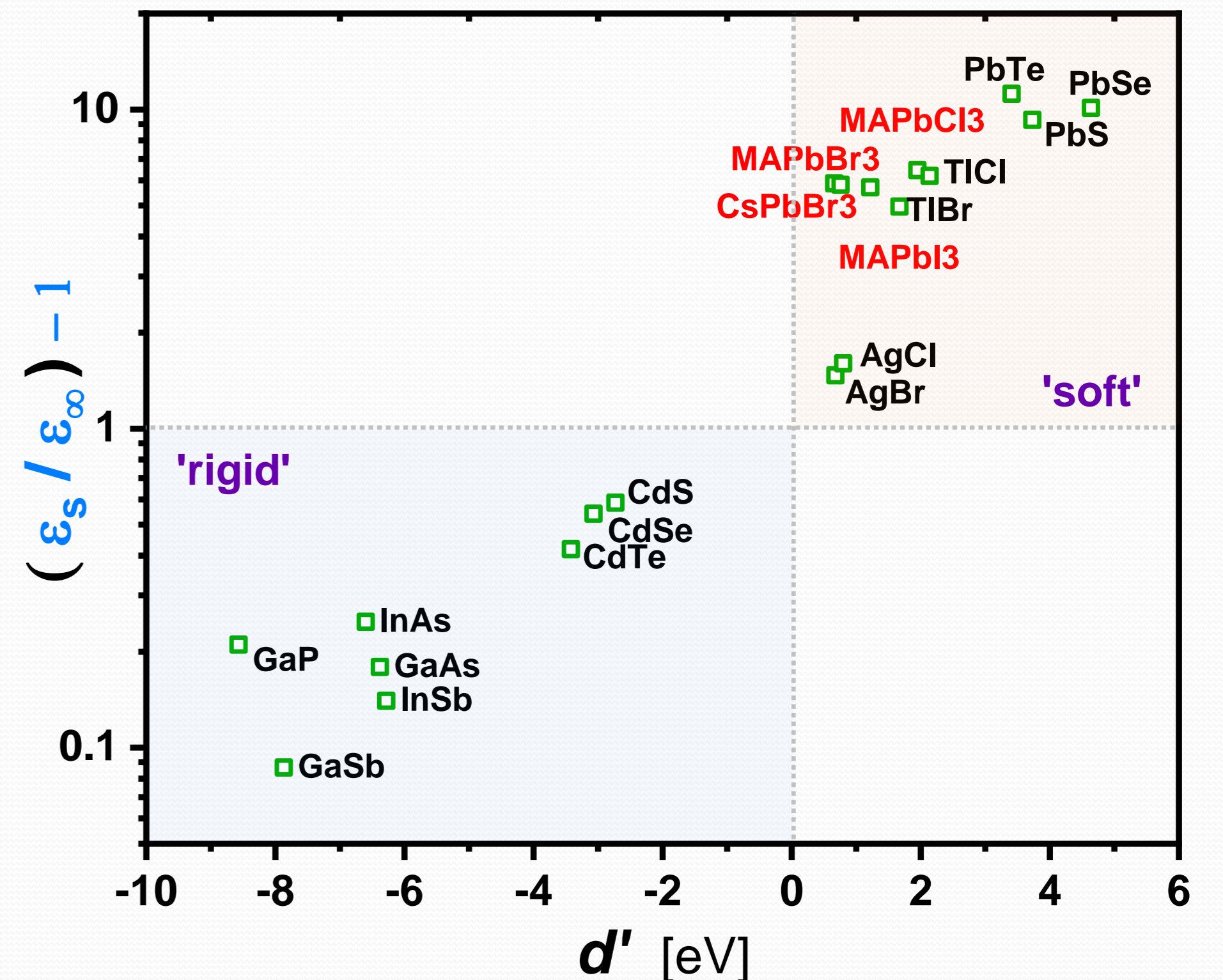
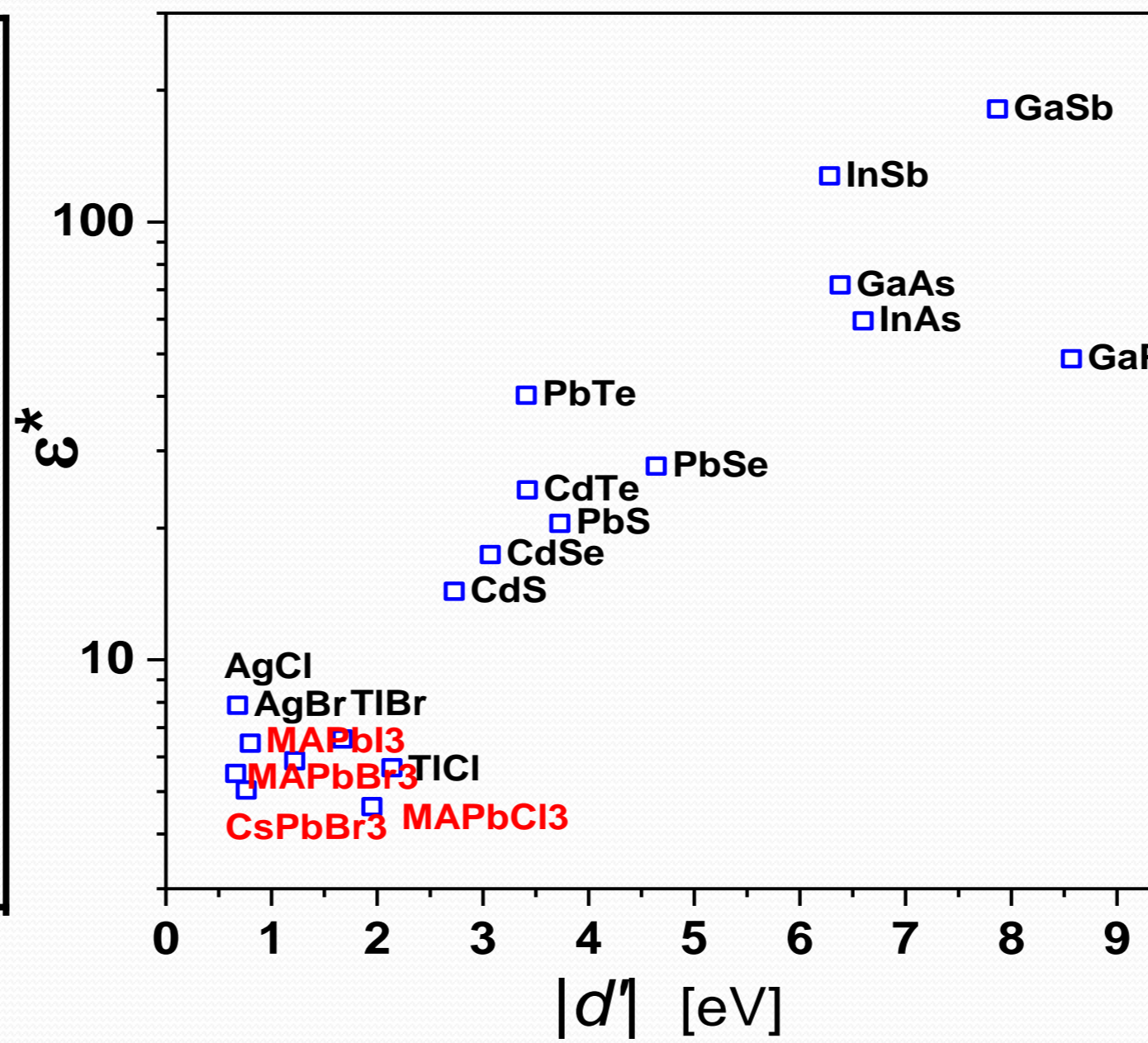
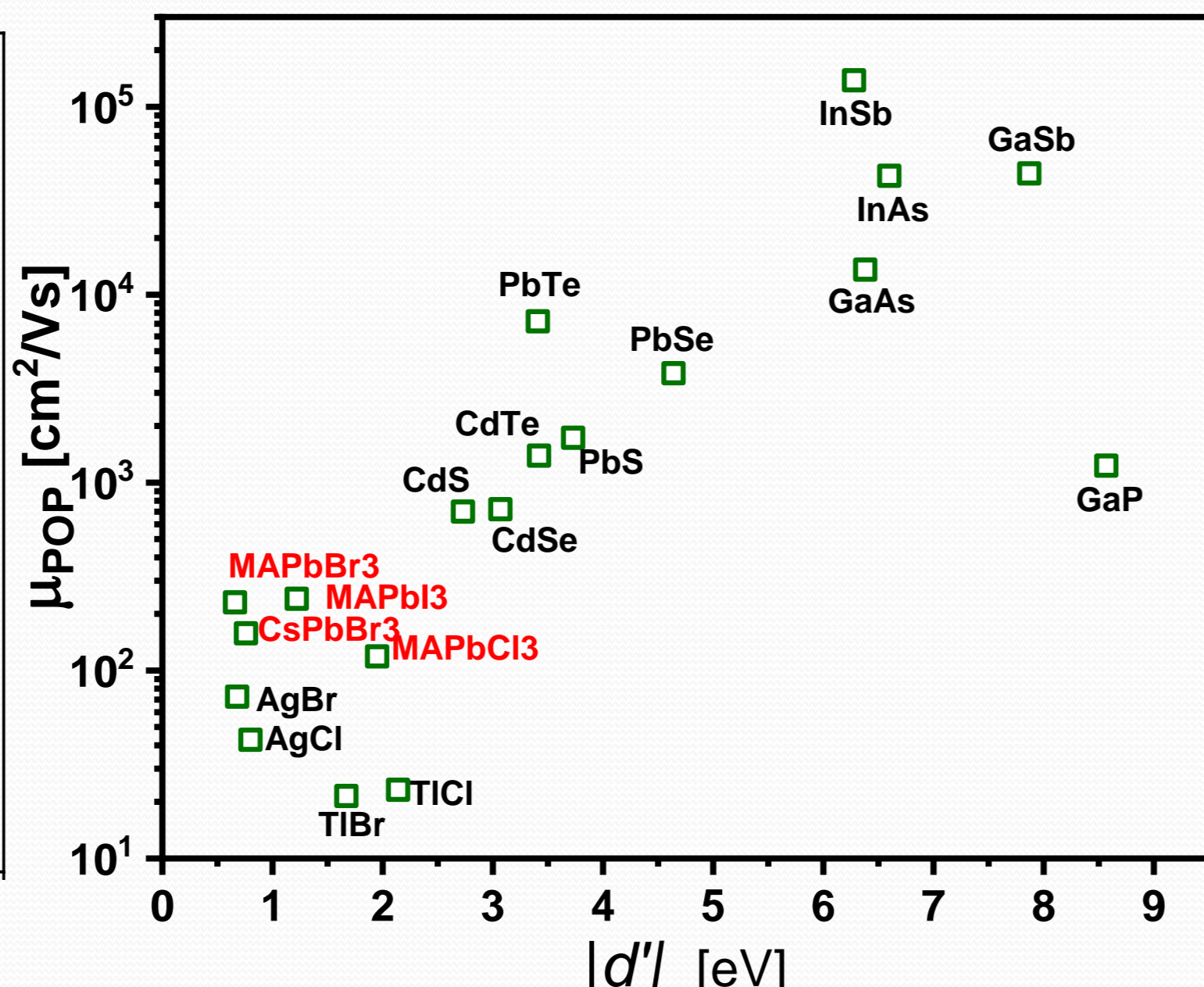
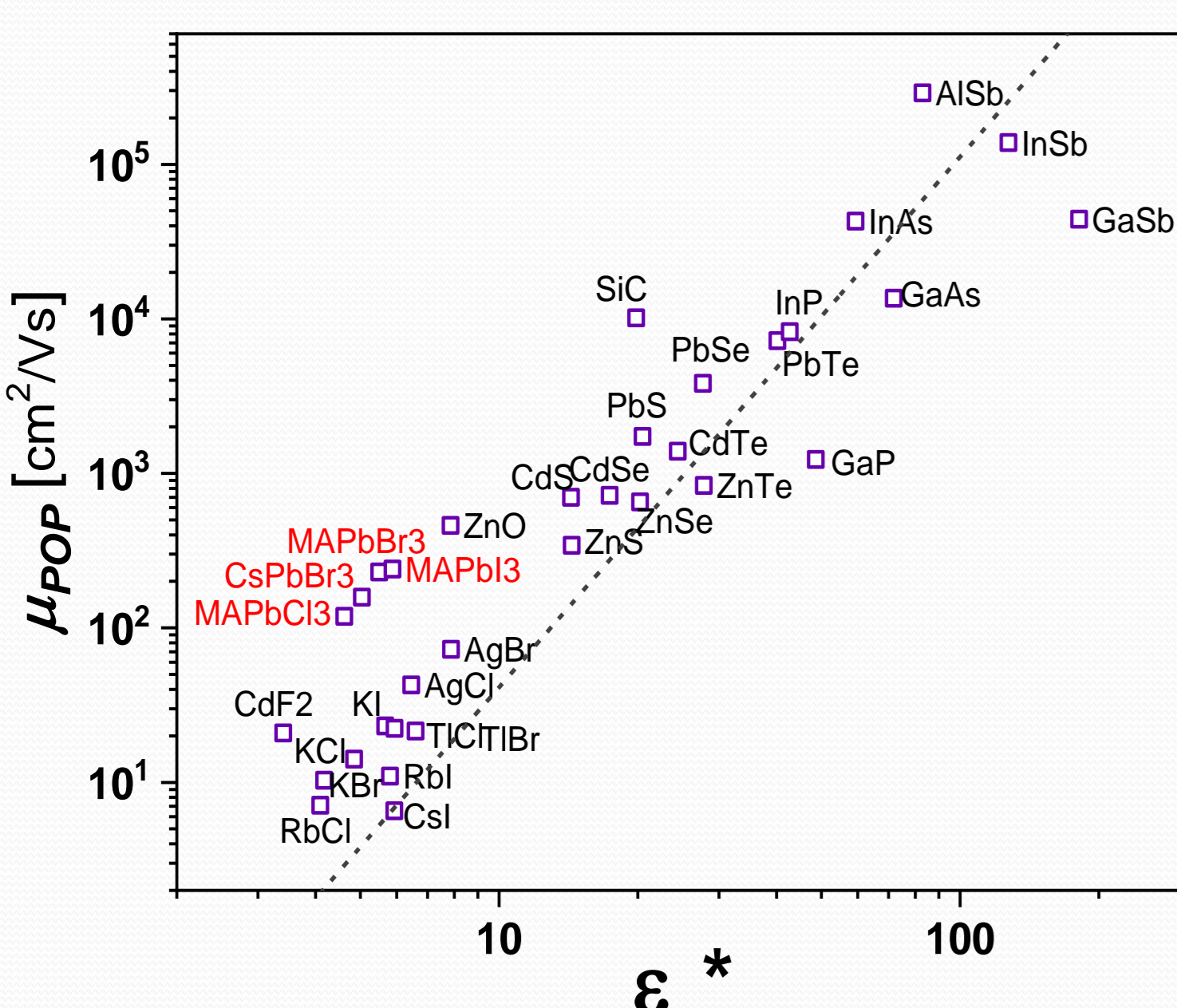


Stillman, G. E. & Wolfe, C. M. *Electrical characterization of epitaxial layers*. *Thin Solid Films* 31, 69–88 (1976).



4 Exploring scattering by POP

Scattering potential: $U_{POP}(r) \propto \frac{q^*}{V_u}$; $\frac{q^*}{V_u} \equiv$ Effective charge density during vibration in a heteropolar system ; $\left(\frac{q^*}{V_u}\right)^2 \propto \frac{\omega_{LO}^2}{\epsilon_s} \left(\frac{\epsilon_s}{\epsilon_\infty} - 1\right) = \omega_{LO}^2 \left(\frac{1}{\epsilon_\infty} - \frac{1}{\epsilon_s}\right) = \frac{\omega_{LO}^2}{\epsilon^*}$



Plotting μ_{POP} for $T=300\text{K}$ as a function of ϵ^* and $|d'|$ shows that mobility increase with higher ϵ^* and $|d'|$.
 ϵ^* increase as $\epsilon_s \rightarrow \epsilon_\infty$, while at the limit where $\epsilon_s \gg \epsilon_\infty$, $\epsilon^* \rightarrow \epsilon_\infty$

Lower $|d'|$ results in increasing ϵ_s w.r.t. ϵ_∞ . \rightarrow the energy-cost to screen electric-fields is smaller \rightarrow tolerant to charged defects.

We conclude that ‘soft’ materials are regarded as such with highly-polarizable bonds (i.e., $\epsilon_s \sim 2 \cdot \epsilon_\infty$), where d' is expected to be positive, suggested to possess in-band berried defect states, and therefore, defect tolerant (see 2)